

1. Record Nr.	UNINA9910782514003321
Autore	Domke Christine
Titolo	Besprechungen als organisationale Entscheidungskommunikation [[electronic resource] /] / Christine Domke
Pubbl/distr/stampa	Berlin, : De Gruyter, 2006
ISBN	1-282-19534-4 9786612195341 3-11-020159-3
Descrizione fisica	1 online resource (268 p.)
Collana	Linguistik, Impulse & Tendenzen, , 1612-8702 ; ; 18
Classificazione	ER 990
Disciplina	658.4/03
Soggetti	Decision making Personnel management - Decision making Associations, institutions, etc - Decision making
Lingua di pubblicazione	Tedesco
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Frontmatter -- Inhalt -- I Zur Einführung -- 1 Zum Spannungsfeld und zum Aufbau der Arbeit -- 2 Besprechungen und ihre Besonderheiten -- II Der methodologisch-theoretische Zugang -- 3 Der Weg zum Gegenstand und zur Untersuchungsperspektive -- III Empirische Analysen -- 4. Grundsätzliches zum Interaktionssystem Besprechung -- 5. Spezifische Elemente und Bearbeitungsmodi der Besprechung -- IV Zum Abschluss -- 6. Besprechungen als Entscheidungskommunikation -- Backmatter
Sommario/riassunto	Communication in organizations takes place under certain circumstances which demand specific analytical approaches. The current study focuses on the following questions: How can meetings be analyzed in relation to the organization in which they take place? How can the often criticized complexity of such meetings be comprehended? What role do decisions play in their comprehension? A special research perspective on this form of organizational communication is developed based on empirical data, conversation analysis and system theory.

2. Record Nr.	UNINA9910831013903321
Autore	Xia Fangzhou
Titolo	Active Probe Atomic Force Microscopy : A Practical Guide on Precision Instrumentation // by Fangzhou Xia, Ivo W. Rangelow, Kamal Youcef-Toumi
Pubbl/distr/stampa	Cham : , : Springer International Publishing : , : Imprint : Springer, , 2024
ISBN	3-031-44233-4
Edizione	[1st ed. 2024.]
Descrizione fisica	1 online resource (383 pages)
Altri autori (Persone)	RangelowIvo W Youcef-ToumiKamal
Disciplina	502.82
Soggetti	Measurement Measuring instruments Electronics Mechatronics Spectrum analysis Microtechnology Microelectromechanical systems Measurement Science and Instrumentation Electronics and Microelectronics, Instrumentation Spectroscopy Microsystems and MEMS
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Nota di contenuto	Introduction -- Active Probe Design and Fabrication -- Advanced Applications of Active Probes -- Atomic Force Microscope Designs -- AFM System using Active Probe -- A Low-cost AFM Design for Engineering Education -- Appendix.
Sommario/riassunto	From a perspective of precision instrumentation, this book provides a guided tour to readers on exploring the inner workings of atomic force microscopy (AFM). Centered around AFM, a broad range of mechatronic system topics are covered including mechanics, sensors, actuators, transmission design, system identification, signal processing, dynamic

system modeling, controller. With a solid theoretical foundation, practical examples are provided for AFM subsystem level design on nano-positioning system, cantilever probe, control system and system integration. This book emphasizes novel development of active cantilever probes with embedded transducers, which enables new AFM capabilities for advanced applications. Full design details of a low-cost educational AFM and a Scale Model Interactive Learning Extended Reality (SMILER) toolkit are provided, which helps instructors to make use of this book for curriculum development. This book aims to empower AFM users with deeper understanding of the instrument to extend AFM functionalities for advanced state-of-the-art research studies. Going beyond AFM, materials presented in this book are widely applicable to precision mechatronic system design covered in many upper-level graduate courses in mechanical and electrical engineering to cultivate next generation instrumentalists. Presents the instrument design details of atomic force microscopy with focus on active cantilever probes; Includes examples and exercises to boost understanding of AFM subsystem design, fabrication and integration; Imparts a hands-on curriculum for precision mechatronics and instrumentation with AFM and digital twin simulators.

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